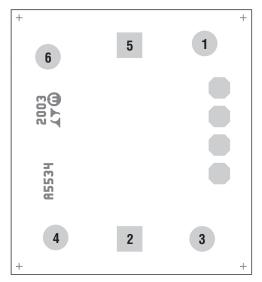


#### LT5534

## 50MHz to 3GHz RF Power Detector with 60dB Dynamic Range



30mils  $\times$  33mils, 8mils thick. Connect Backside to: GND

#### PAD FUNCTION

- 1. ENABLE
- GND
- 3. V<sub>OUT</sub>
- 4. V<sub>CC</sub> 5. GND

#### **DIE CROSS REFERENCE**

LTC® Finished	Order
Part Number	Part Number
LT®5534	LT5534DICE

Please refer to ADI standard product data sheet for other applicable product information.

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#### **ABSOLUTE MAXIMUM RATINGS**

(Note 1)

Power Supply Voltage ......5.5V 

#### **DICE/DWF ELECTRICAL TEST LIMITS** $T_A = 25^{\circ}C$ . $V_{IN} = 3.6V$ , unless otherwise noted.

PARAMETER	CONDITIONS	MIN	MAX	UNITS
Power Supply				
Supply Voltage		2.7	5.25	V
Supply Current (Note 2)	EN = High	5	9	mA
Shutdown Current	EN = Low		10	μА
Output Interface				
Output DC Voltage	No RF Input Signal		450	mV

Note 1: Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. Exposure to any Absolute Maximum Rating condition for extended periods may affect device reliability and lifetime.

Note 2: Supply Current is production tested at  $T_A = -10^{\circ}C$  and  $T_A = +25^{\circ}C$ .

# DICE/DWF SPECIFICATION

## LT5534

#### **REVISION HISTORY**

REV	DATE	DESCRIPTION	PAGE NUMBER
0	1/14	Initial release	_
Α	12/24	Updated Order Information	1

### DICE SPECIFICATION

LT5534

Wafer level testing is performed per the indicated specifications for dice. Considerable differences in performance can often be observed for dice versus packaged units due to the influences of packaging and assembly on certain devices and/or parameters. Please consult factory for more information on dice performance and lot qualifications via lot sampling test procedures.

Dice data sheet subject to change. Please consult factory for current revision in production.